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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,625	TERAO ET AL.	
Examiner	Art Unit	
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INT	INTERFERENCE SEARCHED		
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SEARCH NO (INCLUDING SEARCH)
·	DATE	EXMR
See EAST search history	11/28/2006	ADF
Inventor search	11/28/2006	ADF
Consulted with Jeffrey Barton and Nam Nguyen	11/28/2006	ADF
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